LAB4D: A Low Power, Multi-GSa/s, Transient Digitizer with Sampling Timebase Trimming Capabilities

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Abstract

The LAB4D is a new application-specific integrated circuit (ASIC) of the Large Analog Bandwidth Recorder and Digitizer with Ordered Readout (LABRADOR) family, for use in direct wideband radio frequency digitization such as is used in ultrahigh energy neutrino and cosmic ray astrophysics. The LAB4D is a single channel switched-capacitor array (SCA) 12-bit sampler with integrated analog-to-digital converters (ADC), developed in the TSMC 0.25 µm process. The LAB4D, operating at 3.2 GSa/s, contains 4096 total samples arranged in 32 windows, for a total record length of 1280 ns. The 3 dB bandwidth is approximately 1.3 GHz, with a directly-coupled 50 Ω input. This represents a factor of 16 increase in the sample depth and an increase in analog bandwidth and sampling depth in comparison to the previous generation LAB3 digitizer. Individually addressable windows allow for sampling and digitization to occur simultaneously, leading to nearly deadtime-free readout for kHz readout rates. All biases and current references are generated via internal digital-to-analog converters (DACs), resulting in a stand-alone digitizer with no additional support circuitry. In addition, the LAB4D contains sample cell timebase trimming capabilities, reducing the intrinsic sample-to-sample time variance to less than 5 ps; an improvement of about 80%. This allows the LAB4D to be used in precision timing applications with minimal post-hoc calibration.

Keywords: Electronic detector readout concepts, Front-end electronics for detector

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1. Introduction

There has been an increasing interest in the development of CMOS switched capacitor array (SCA) samplers due to their low-cost and high performance. These devices have been thoroughly written about in high energy physics literature [1][2][3][4][5][6]. Many have accomplished digitization speeds high enough for greater than Nyquist sampling of a GHz analog bandwidth signal. These ≥GSa/s devices have been used in experiments designed to detect neutrinos [7][8][9], gamma-rays [10], and for precision photon timing [11][12]. SCA samplers are cost-effective alternatives to analog-to-digital converters (ADCs) due to their excellent timing recording and high resolution amplitude [13][14].

The analog nature of the sampling in SCA samplers also limits their widespread acceptance, requiring resource and time consuming calibration requirements to achieve high performance. To simplify the integration and usage of these digitizers, the LAB4 design was developed, with a primary goal of demonstrating the ability to trim the inherently non-uniform timebase generated by the CMOS voltage-controlled delay line (VCDL) using simple internal digital-to-analog converters (DACs). A further simplification involved moving all previously-external voltage biases and current references to internal DACs, resulting in no additional support electronics for digitization.

A further limitation of SCA samplers is the long readout time. While data can be acquired at GSa/s rates, data readout typically is significantly slower (tens of MSa/s). In previous generation ASICs, this implied a high deadtime associated with each readout. For example, a 1024 sample readout at 10 MSa/s would result in the digitizer being unavailable for 102.4 µs, which, at a 1 kHz trigger rate would result in 10% deadtime. The LAB4 series integrates improvements stemming from the buffered LABRADOR (BLAB) series of ASICs [15] to achieve simultaneous sampling and readout by dividing the total number of samples into windows which can be written to or read out separately. This allows a significant reduction in deadtime - assuming a random trigger probability, the LAB4D would experience only 0.1% deadtime under the previous example.

The LAB4D, a fourth revision of the LAB4 design, was fabricated in the TSMC 0.25 µm CMOS (LO) process, and packaged in a 48-pin quad-flat-no lead (QFN) package to reduce parasitic bondwire inductance. A die image of the LAB4D ASIC is shown in Figure 1. Results and performance of the LAB4D design will be discussed.

2. Architecture

The LAB4D architecture is a descendant of the LABRADOR-3 (LAB3) design, developed for the Antarctic Impulsive Transient Antenna (ANITA) ultra-
The ANITA experiment requires \( \sim 100 \) sampling channels over 200–1200MHz \([16]\). Commercial flash ADCs were impractical due to cost and power limitations. The LAB3 ASIC has been successfully deployed in four ANITA long-duration balloon flights, and the LAB4D is scheduled to be deployed in future missions.

A variety of different CMOS switched capacitor array architectures that are similar to the LAB4D have been discussed in the literature \([17]\). A compact, minimal storage array was used in order to limit the parasitic and storage capacitance of the SCA \([18]\). The decision to pursue a compact storage matrix architecture was symbiotic with similar designs being explored for Monolithic Active Pixel Sensors (MAPS) for charged particles \([19][20]\). Details on the architectures of the previous versions of the LABRADOR family, the theory of operation, and specifications, have also been discussed in the literature \([21]\).

A simplified block diagram of the LAB4D is shown in Figure 2. The LAB4D consists of a “primary” sampling array arranged as two blocks of 64 sample-and-hold cells which are directly connected to an externally-terminated 50\( \Omega \) RF input. These blocks are transferred to one of four 64-sample intermediate storage arrays. Two of the intermediate storage arrays (128 total samples) are then transferred to the main storage array, which is organized into 32 “windows” (128 samples each), corresponding to 4096 total samples. Windows in the main storage array can be written to and read from in a random-access man-
ner using an externally-provided write and read address. The window address is selected for readout by an independent RF trigger unit within the ANITA instrument crate. During readout, a selectable window is digitized in parallel via a Wilkinson (ramp) ADC, and then the final digitized data is shifted out using a high-speed LVDS output. Readout speeds of 20 µs per window are practical, resulting in a readout speed of 6.4 MSa/s. A timing diagram showing the two-stage transfer to the main storage array is shown in Figure 3.

Figure 2: Simplified block diagram for the LAB4D. RF signals are sampled in the primary array, transferred to a secondary storage array in 64-sample chunks, and finally to a 128-sample window in the main storage array of 32 windows. Secondary storage alternates between even (A1/A2) and odd (B1/B2) windows depending on the clock cycle. Timing for sampling and transfer is controlled via configurable taps from a DLL driven by the master clock, and controlled and trimmed via internal DACs. Digitization is performed via an on-die Wilkinson ADC, with programmable ramp current and timing. Data is then read out via a serial LVDS output. DLL configuration, digitization control, and DAC values are all programmable via a custom serial interface.

The LAB4D internal configuration and readout control is performed using a custom 4-wire serial interface which accesses an address space of 256 16-bit registers. Internal timing of the LAB4D is controlled via configurable taps of the VCDL. The overall speed of the VCDL is controlled via a delay-locked loop (DLL) which synchronizes it to an externally-supplied master clock. Individual delays of the VCDL are tunable using 128 individual trim DACs, which allows for the creation of a uniform timebase for the LAB4D. Additional DACs are used to provide voltage biases for the analog transfer and digitization, which
allows for power consumption optimization.

2.1. Sampling Array

As shown in Figure [2], the LAB4D features a unique two-stage sample transfer architecture which allows for an effective doubling of the settling time into the main storage array. In short, the data from the primary sampling array is written 64-samples at a time into the secondary storage arrays, A1/A2/B1/B2, and then written 128 samples at a time into the selected window in the main storage array. The result is an improved decoupling of the primary array from the sampling array which is necessary given the fact that the main storage array occupies most of the physical space of the ASIC (see Figure [1]) and the samples that are being stored must travel long routes across the chip to reach the designated storage cell.

This sampling array, shown in the block diagram in Figure 3, utilizes what we call a ping-pong intermediate storage cell method. As previously described, there are two sets of 64 sampling cells and these are then paired with two intermediate storage cells. The cells from the primary sampling block are continuously being written to the intermediate storage cells 1 and 2. When intermediate storage cell 1 becomes “full”, intermediate storage cell 2 is then written to while cell 1 writes to the primary storage array. It is the alternating between which sampling array and intermediate storage array the sampling cell writes to that resembles a ping-pong ball constantly changing its side of the table, hence, the origins of “ping-pong” sampling method terminology. The timing diagram, also shown in Figure [3], is another useful means to conceptualize the logic of this process.
2.2. Timing Generation

Timing for the 128 primary sample-and-hold cells in the LAB4D is controlled by taps from the VCDL in the timing generator. Shown in Figure 4, the VCDL is a 128-element delay line, with each element consisting of 2 voltage controlled delays, implemented as current-starved inverters. One control voltage is common to all 128 elements, and the second is an individual trim voltage, separate for each element.

The total delay of the VCDL is locked to an external clock using a delay-locked loop (DLL) which compares the external clock after propagating through
the VCDL to an undelayed version of the same clock. The comparison output (a simple exclusive-or) is then fed into a charge pump which develops a control voltage used to drive the delay voltage common to all elements in the VCDL. To compensate for additional delays in the DLL logic, the feedback signal can be selected from any tap in the VCDL (as a coarse delay), and a separate voltage-controlled delay ("VtrimT") acts as a fine delay. The purpose of the DLL and the common delay in each element is to reduce the overall temperature variation of the sampling speed of the LAB4D.

Figure 4: **Upper**: Simplified schematic diagrams of the variable inverter types used for timing generation in the LAB4D **Lower**: Simplified block diagram of a LAB4D delay block

### 2.3. LABRADOR Series

Four generations of LABRADOR architecture ASICs have been designed, fabricated and tested. The features of the LAB4D and LAB3 are summarized in Table [I]. All of these ASICs have been fabricated in the TSMC 0.25 μm CMOS (LO) process and all previous generations were packaged in a 64-pin plastic TQFP package. The LAB4D was the first to utilize a 48-pin QFN package in order to reduce lead inductance and for improved compactness.
Table 1: Summary of LABRADOR Specifications and Improvements

<table>
<thead>
<tr>
<th>Item</th>
<th>LAB3</th>
<th>LAB4D</th>
</tr>
</thead>
<tbody>
<tr>
<td># RF Inputs</td>
<td>9</td>
<td>1</td>
</tr>
<tr>
<td>Sample-and-hold cells per input</td>
<td>260</td>
<td>128</td>
</tr>
<tr>
<td>Total number of samples</td>
<td>2340</td>
<td>4096</td>
</tr>
<tr>
<td># of ADCs</td>
<td>2340</td>
<td>128</td>
</tr>
<tr>
<td>Sampling speed control</td>
<td>Analog</td>
<td>Delay-locked loop</td>
</tr>
<tr>
<td>RMS of sampling intervals</td>
<td>50</td>
<td>2.5</td>
</tr>
<tr>
<td>3dB bandwidth for 50 ohm input (MHz)</td>
<td>900</td>
<td>1300</td>
</tr>
<tr>
<td>Sampling speed [GSa/s]</td>
<td>2.6</td>
<td>3.2</td>
</tr>
<tr>
<td>Package</td>
<td>128-pin QFP</td>
<td>48-pin QFN</td>
</tr>
</tbody>
</table>

Both versions of the LABRADOR ASIC feature a usable signal voltage range of 0–2.5V. The LAB4Ds were designed as single channel RF digitizers in order to remove bondwire and on-die coupling that was present in the LAB3 series. A unique feature of the LAB4D is the ability to tune the individual sampling intervals in the hardware using the built-in trim DACs. The use of Gray code was also implemented to prevent spurious outputs. These improvements, and others, are discussed in more detail in the following sub-sections.

A general overview of the LAB4D signal processing is shown in Figure 2. Looking at this figure, one can follow that a RF input generates 128 sampling intervals that run in parallel with a voltage-controlled delay line and delay-locked-loop. The delay-locked-loop (DLL) fixes the total delay to exactly one reference clock period. At 25 MHz, the sampling rate is 3.2 GSa/s. The built-in trim DACs allow mitigation of the sampling differential non-uniformity.

The analog bandwidth of the LAB4D has been expanded in the high frequency region by 400 MHz in comparison to previous generations of the ASIC. The LAB4D has a storage array of 4096 cells, arranged in 32 blocks of 128. In the ANITA mission, 8 of these blocks will be read out of each event, which at 3.2 GSa/s results in 320 ns duration waveforms for each event; a 100% increase in comparison to the LABRADOR3.

2.4. Implementation

Characterization of the LAB4D performance was performed using a 12-channel digitizer designed for the ANITA experiment, the Sampling Unit for Radio Frequencies, version 5 (SURFv5). The SURFv5 is a CompactPCI-compatible 6U PCB, with a single Xilinx Artix-7 field programmable gate array (FPGA) interfacing with all LAB4Ds and providing a CPU interface for data readout and LAB4D configuration.

1This is a desired operating point and not a design limitation
The incoming RF signals are conditioned with a 200–1200MHz bandpass using a Mini-Circuits HFCV-145+ low-pass and an LFCN-1200+ high-pass filter. In addition, a copy of the incoming signal was coupled off using a Mini-Circuits TCD-13-4X+ for RF power monitoring, and a calibration signal common to all LAB4Ds was coupled in using an identical coupler. Finally, the AC-coupled signal was 50 Ω terminated to an adjustable DC voltage.

A total of nine SURFv5s were manufactured, and two SURFv5s have currently been tested and characterized, for a total of 24 LAB4Ds. Performance of the 24 LAB4Ds were broadly comparable. Each SURFv5 was assigned an identifier associated with a popular Oahu surfing location, as shown in Figure 5.

Figure 5: Image of the Sampling Unit for Radio Frequencies, version 5 (SURFv5), used for LAB4D characterization. Each SURFv5 contains 12 LAB4D ASICs, packaged in a 48-pin quad-flat no-lead (QFN) package. The LAB4Ds are visible on the left section of the board immediately after the RF conditioning components. The printed circuit board dimensions are 6.3 x 9.2 inches.

3. Results

The performance of the LAB4D ASIC as implemented on the SURFv5 was characterized to determine its suitability for RF digitization. Specifically, the
noise level, linearity, working range, sample-to-sample timing variation, and analog bandwidth were measured. Next, the stability of these measurements with respect to operating temperature was characterized. Finally, the overall power consumption was determined.

Temperature variations were investigated using 3 LAB4Ds which were coupled using thermal paste to a copper heat sink with a Peltier heater/cooler with a separate heat sink on the opposite side, as well as a thermometer for monitoring the LAB4D temperature. Current through the Peltier device was varied to control the LAB4D temperature.

3.1. Noise

Each individual storage cell in the main storage array develops a slightly different DC offset due to non-uniformity in the fabrication process. These offsets, called “pedestals”, must be measured and removed to recover the input signal. Subtraction of the individual pedestal can easily be done at the point when each sample is read out, since each sample’s subtraction is independent. The measured pedestal values for all LAB4D ASICs on a single SURFv5 is shown in Figure 6. The intrinsic pedestal variation results in a relatively minor \( \sim 3.7\% \) reduction in total dynamic range.

Once the individual pedestals are measured and removed, a histogram of the measurements for a terminated input was obtained to determine the overall KTC noise contributions of the switched capacitor based sampling cells and the two storage cells of the LAB4D. The observed total noise is roughly saturated by these contributions and was measured to be 2.19 ch, which corresponds to approximately 1 mV using a nominal DC transfer function of 2 ch/mV. This noise level is broadly consistent with other SCA samplers and previous generation LABRADOR ASICs and is not expected to be an operational limitation.

Figure 6: Left: Distribution of measured pedestal values for a typical LAB4D. The input DC voltage for this measurement was 0.74 V. Measured pedestals ranged from 1600–1750 counts, which corresponds to approximately \( \sim 3.7\% \) of the total dynamic range. Right: Terminated input histogram. The spread in measured values is 2.19 ADC channels, which corresponds to 1.08 mV using the DC transfer function in the linear region of 2 mV/ch.
3.2. Linearity

After pedestal subtraction, the linearity of the digitization of the LAB4D was characterized. This was performed by conducting single-parameter scans of the DC input voltage to the LAB4D. The overall linearity and sample dependence is shown in Figure 7. The sample-to-sample variations of the transfer slope are shown in this plot containing all sample cells. Over a 1 V span from 500–1500 mV, the DC transfer curve shows an integral non-linearity of better than 2.5% for most of the region, as shown in Figure 8.

Temperature variations of the transfer curve are shown in Figure 9. The transfer curve slope varied by approximately 0.1%/1°C. In addition, pedestal offsets were measured to vary by approximately 0.05%/1°C.

Figure 7: DC scan linearity 1024 LAB4D sample cells. The linear offsets are the result of various pedestal offsets used for each cell.
Figure 8: A best linear fit of a large number of single-parameter DC scans of a single sample cell is shown where there is an integral non-linearity of better than 2.5% for about 75% of the region.

Figure 9: Multiple DC scans of a single sample cell of the LAB4D at various temperatures where the slope is shown to increase with decreased temperature (Color on-line).
3.3. Sample-to-sample timebase variation

The DLL is first optimized by sampling a 235 MHz sine wave. The individual trim DACs are set to a common approximate delay, which assigns a portion of the delay for each element to be controlled by the trim delay, and the remainder to be controlled by the DLL. Because of internal routing in the delay line, even and odd samples are set to different initial values. Then, a sine wave is fit to a single window of data and $V_{trimT}$ is adjusted so that the fit frequency matches the input frequency. An example of this optimization can be seen in Figure 10. At this point, the average sampling speed of the LAB4D is 128 times the external clock, and the sample-to-sample timing variations can then be tuned.

![Figure 10: Left: Window-to-window stitching of a 235MHz sine wave before initial DLL tuning. The vertical tan line represents the location of the two window (128 sample) boundaries. Right: Window-to-window stitching of a 235 MHz sine wave after tuning. The previously visible window boundary is now eliminated.](image)

The individual sample timing is then trimmed using the individual trim DACs. Because the DLL acts to keep the overall delay of the VCDL the same, adjustments in any single sample trim DAC will result in the corresponding adjustment of the timing of that sample and all other samples. That is, slowing down a single sample by 1% using the trim DACs will result in the remaining samples speeding up by $\frac{1}{127}\%$ to compensate.

We therefore use an iterative minimization procedure to determine all trim DAC values simultaneously. This procedure consists by measuring the fraction of observed samples where the observed value (relative to the subsequent sample) crosses the DC pedestal ("zero-crossing fraction"), either positive-going or negative-going, for 8000 separate waveforms. This fraction is a simple measure of the width of the time sample, and should be constant if the sample timing is regular. For samples that have a zero-crossing fraction greater than the average, the trim DAC value is decreased, speeding up that sample. Likewise, samples that have a lower-than-average zero-crossing fraction are slowed down by increasing the trim DAC value.

This procedure is repeated multiple times, which progressively reduces the variation in the timebase. Within approximately 10 iterations, the RMS vari-
ation in the sample-to-sample timing is reduced below 5 ps. The iterative procedure eventually (after 30-40 iterations) reaches RMS timing variations of approximately 2.5 ps. The improvement in timing over iteration count, as well as the sample-to-sample timing, can be seen in Figure 11. The last intrawindow delay \((t_{127} - t_{126})\) contains an unknown extra delay which is currently under investigation, and results in this sample timing being a noticeable outlier from the other samples. This should be further adjustable by assigning more overall delay to the trim DACs in the calibration procedure.

![Figure 11: Left: Measured sampling intervals versus sample number before and after tuning. Routing in the LAB4D delay line results in an odd/even sample initial timing variation, which is eliminated after tuning. The final sample timing is currently under investigation. Right: Improvement in the RMS of the individual sample timings as a function of the number of iterations. The RMS decreases to below 5 ps within 10 iterations, and further reduces to approximately 2.5 ps after 30-40 iterations.](image)

Finally, the stability of the timebase with respect to temperature variation was also investigated. First, the DLL was tuned at a temperature of 30° C and a 210 MHz sine wave was digitized by the LAB4D. Data was then taken between 10° C and 60° C in 10° C intervals, with the DLL enabled, and again with the DLL function disabled, in order to investigate the reduction in temperature sensitivity due to the DLL. The sampling rate was manually set by fixing the voltage which controls the common delay in the VCDL via an internal DAC.

The sampling frequency of the LAB4D was determined again using the zero-crossings of the recorded data, and the sampling frequency versus temperature is shown in Figure 12. With the DLL disabled, the sampling frequency had a strong temperature dependence, between 500 – 2000 ppm/°C. The action of the DLL reduces that temperature dependence to less than 3 ppm/°C, as was expected.

Temperature variations also affect the regularization of the sampling timebase. To explore this, the trim DACs were briefly calibrated at both 25° C and 50° C, and then the sample-to-sample time variation was measured from 10–75° C in 5° C steps. The DLL was enabled for all tests. These results are also shown in Figure 12. The sampling variations show a strong temperature
dependence, however, over a range of ±10 °C the RMS time variations remained within a factor of 2 of their original calibrations.

Figure 12: **Left**: Measured sampling frequency as a function of temperature both with DLL enabled (solid line) and DLL disabled (dashed line) where the sampling frequency shown to be between 500 – 2000 ppm/°C, is reduced to less than 3 ppm/°C by the DLL. **Right**: RMS variations of the sample timebase as a function of temperature when calibrated at room temperature (solid) and 50° C (dashed), with DLL functionality always enabled. Sample-to-sample variability remained within a factor of 2 of the calibration within a range of ±10 °C.

### 3.4. Analog bandwidth

The LAB4D analog bandwidth was measured using the impulse response of the SURFv5. The impulse response was used to avoid effects from sampling persistence [22] which would be present when using a frequency-swept continuous-wave (CW) source. The SURFv5, as was previously mentioned, has an RF input chain consisting of a Mini-Circuits HFCV-145+ and LFCN-1200+ high and low pass filter, respectively, as well as two TCD-13-4X couplers used to couple off a copy of the input signal and to couple in a low-frequency calibration tone. The bandpass of the input chain is primarily determined by the high and low pass filters, which act to block DC and as an antialiasing filter for the digitizer. A high-frequency impulse generated by a Tektronix AWG5104 was digitized by both the SURFv5 and a Tektronix MSO 5204B oscilloscope with a 2 GHz input bandwidth under identical conditions. Waveforms from the SURFv5 were correlated and averaged to produce the upsampled waveform, shown in Figure [13] along with the impulse viewed by the oscilloscope, shown in Figure [14] for comparison.
To extract the small-signal analog bandwidth, the Fourier transform of the impulse response for both the SURFv5 and the oscilloscope were taken using a ±10 ns Hann window around the peak to eliminate effects from reflections due to imperfect input matching at the coaxial cable connections. The SURFv5 input bandpass was then obtained from a test board using a network analyzer and applied to the oscilloscope response. Finally, the LAB4D de-embedded frequency response was obtained by subtracting the measured SURFv5 response from the modified oscilloscope response. The oscilloscope and the de-embedded LAB4D response are shown in Figure 15.

The measured 3 dB point of the LAB4D is approximately 1.3 GHz, with a frequency response flat to within 0.5 dB observed up to 1.1 GHz. This is a conservative measurement, as uncertainty in correlating the corresponding waveforms from the SURFv5 when averaging them will reduce the high-frequency response. The low-frequency response is purely determined by the high-pass filter on the SURFv5. The LAB4D has no intrinsic low-frequency limitation and the frequency response below 200 MHz is expected to be flat. This represents a 44% increase over the LAB3, which had a measured 3 dB point of 900 MHz.
4. Summary

A switched capacitor array device developed in the TSMC 0.25 µm CMOS (LO) process which utilizes a unique “ping-pong” intermediate storage array architecture has been designed, fabricated, and characterized. This ASIC, the LAB4D, has a -3dB upper analog bandwidth limit of greater than 1.3 GHz, a sampling frequency of 3.2 GSa/s (well above Nyquist minimum for the 200-1200MHz ANITA band), a sample window length of 320 ns, and features the unique ability to tune the timebase sampling offsets, reducing the RMS time variance between sample cells to be reliably less than 5 ps.

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